

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (L²-π-MOSVI)

TPC8302

Lithium Ion Battery Applications
 Portable Equipment Applications
 Notebook PCs

- 2.5 V Gate drive
- Small footprint due to small and thin package
- Low drain-source ON resistance: $R_{DS(ON)} = 100 \text{ m}\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 5 \text{ S}$ (typ.)
- Low leakage current: $I_{DSS} = -10 \text{ }\mu\text{A}$ (max) ($V_{DS} = -20 \text{ V}$)
- Enhancement-mode: $V_{th} = -0.5 \sim -1.1 \text{ V}$ ($V_{DS} = -10 \text{ V}$, $I_D = -200 \text{ }\mu\text{A}$)

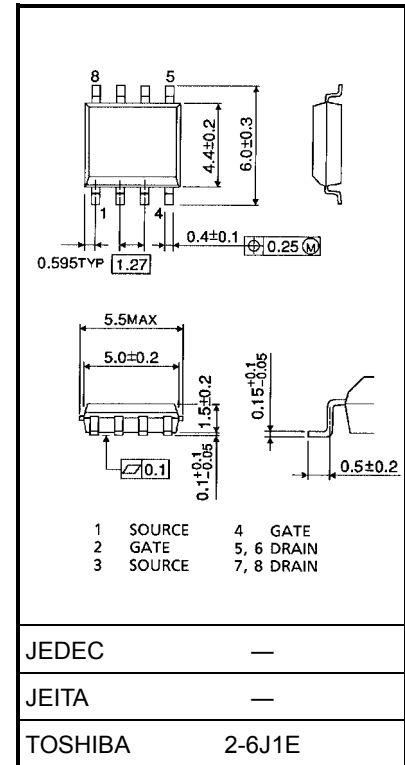
Maximum Ratings (Ta = 25°C)

| Characteristics | | Symbol | Rating | Unit |
|--|---|-----------|----------|------|
| Drain-source voltage | | V_{DSS} | -20 | V |
| Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$) | | V_{DGR} | -20 | V |
| Gate-source voltage | | V_{GSS} | ± 12 | V |
| Drain current | D C (Note 1) | I_D | -3.5 | A |
| | Pulse (Note 1) | I_{DP} | -14 | |
| Drain power dissipation (t = 10s) (Note 2a) | Single-device operation (Note 3a) | $P_D(1)$ | 1.5 | W |
| | Single-devece value at dual operation (Note 3b) | $P_D(2)$ | 1.0 | |
| Drain power dissipation (t = 10s) (Note 2b) | Single-device operation (Note 3a) | $P_D(1)$ | 0.75 | W |
| | Single-devece value at dual operation (Note 3b) | $P_D(2)$ | 0.45 | |
| Single pulse avalanche energy (Note 4) | | E_{AS} | 16 | mJ |
| Avalanche current | | I_{AR} | -3.5 | A |
| Repetitive avalanche energy (Note 2a, Note 3b, Note 5) | | E_{AR} | 0.1 | mJ |
| Channel temperature | | T_{ch} | 150 | °C |
| Storage temperature range | | T_{stg} | -55~150 | °C |

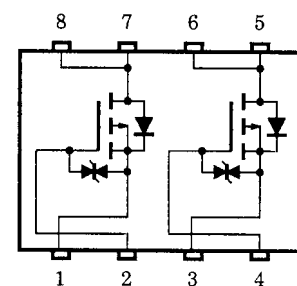
Note: For (Note 1), (Note 2a), (Note 2b), (Note 3a), (Note 3b), (Note 4) and (Note 5), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm



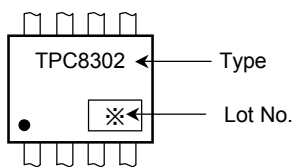
Circuit Configuration



Thermal Characteristics

| Characteristics | | Symbol | Max | Unit |
|---|---|-------------------|------|------|
| Thermal resistance, channel to ambient (t = 10s) | Single-device operation (Note 3a) | $R_{th(ch-a)}(1)$ | 83.3 | °C/W |
| | Single-device value at dual operation (Note 3b) | $R_{th(ch-a)}(2)$ | 125 | |
| Thermal resistance, channel to ambient (t = 10s) | Single-device operation (Note 2a) | $R_{th(ch-a)}(1)$ | 167 | |
| | Single-device value at dual operation (Note 2b) | $R_{th(ch-a)}(2)$ | 278 | |

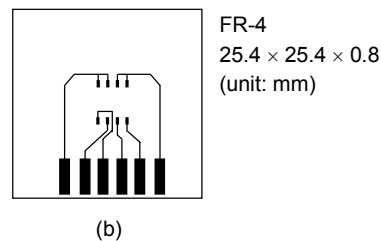
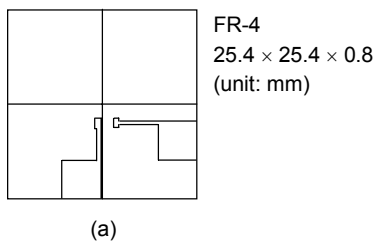
Marking



Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a) b) Device mounted on a glass-epoxy board (b)



Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)

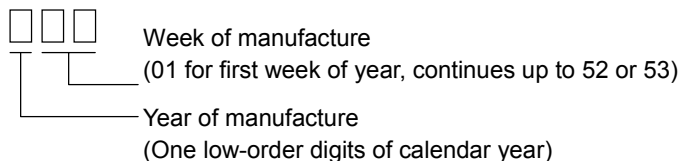
Note 4:

$V_{DD} = -16\text{ V}$, $T_{ch} = 25^\circ\text{C}$ (Initial), $L = 1.0\text{ mH}$, $R_G = 25\ \Omega$, $I_{AR} = -3.5\text{ A}$

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.

※ Weekly code: (Three digits)

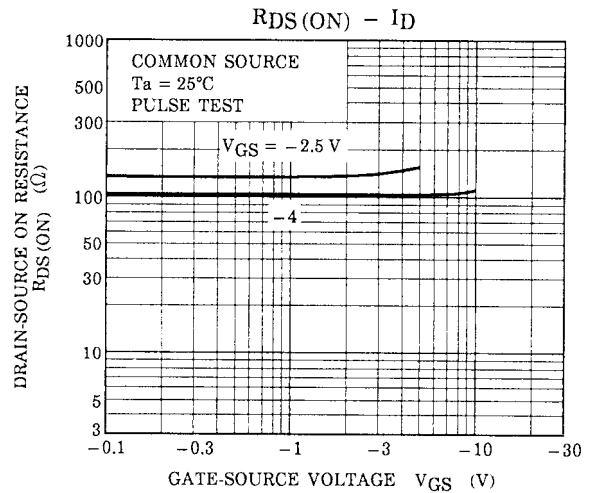
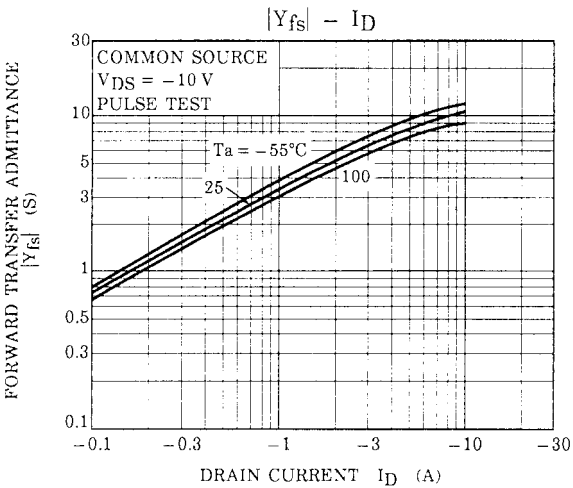
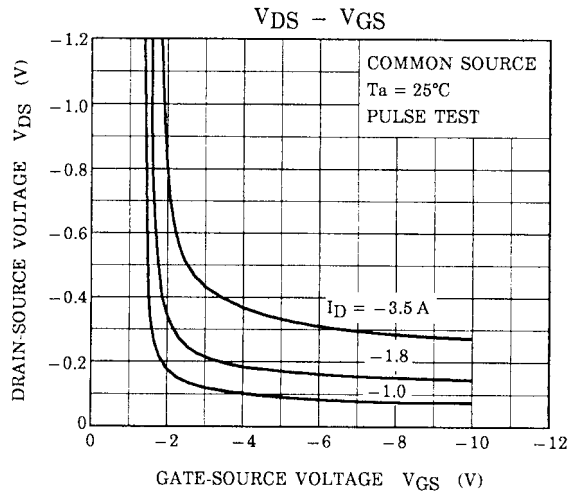
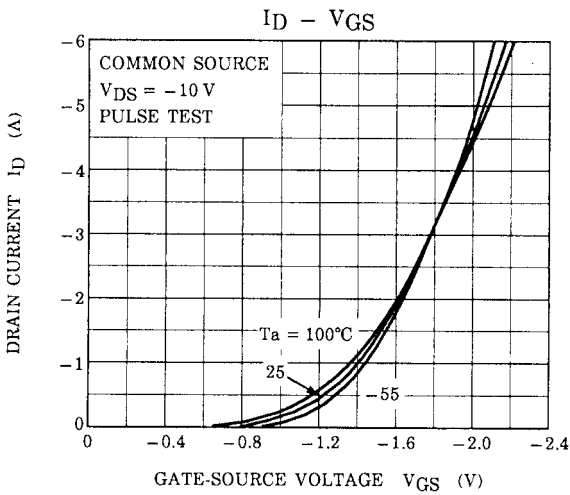
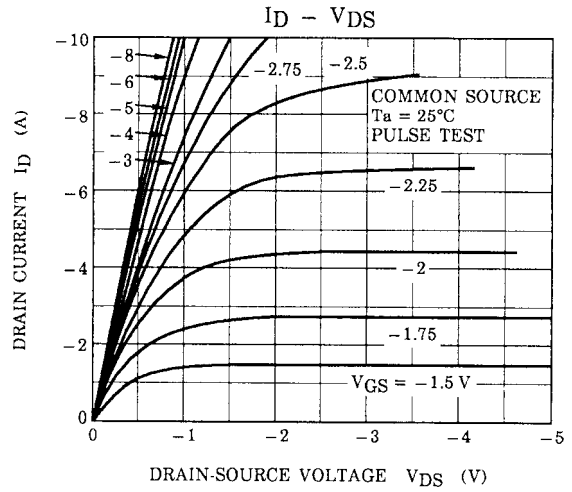
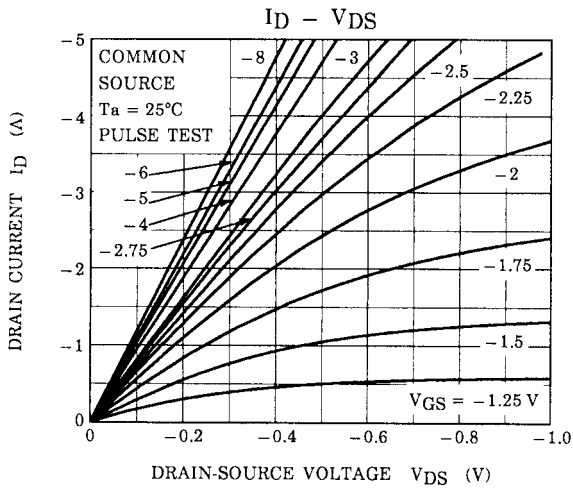


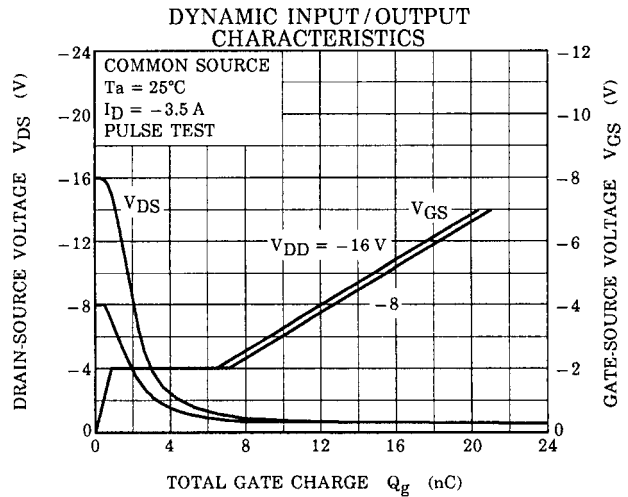
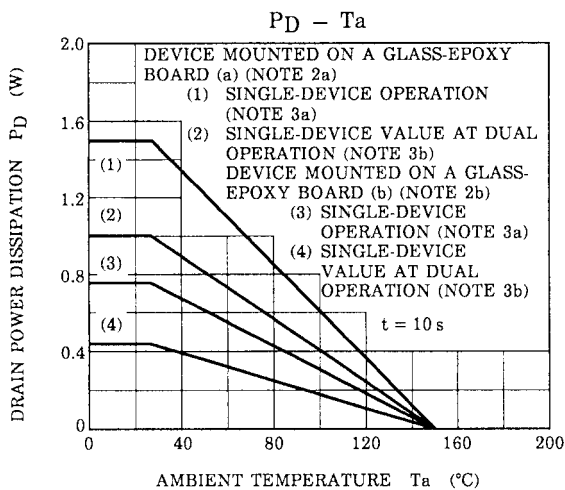
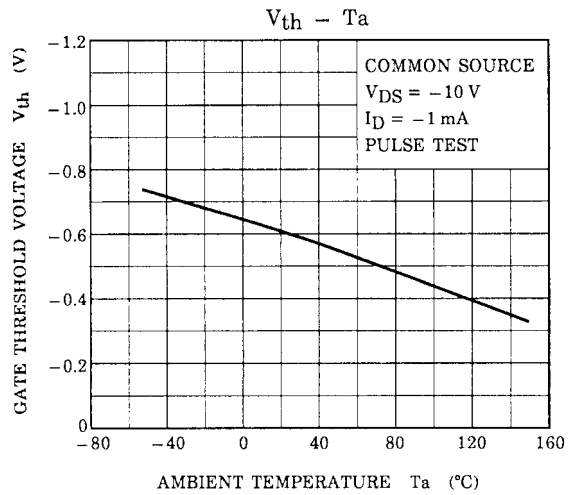
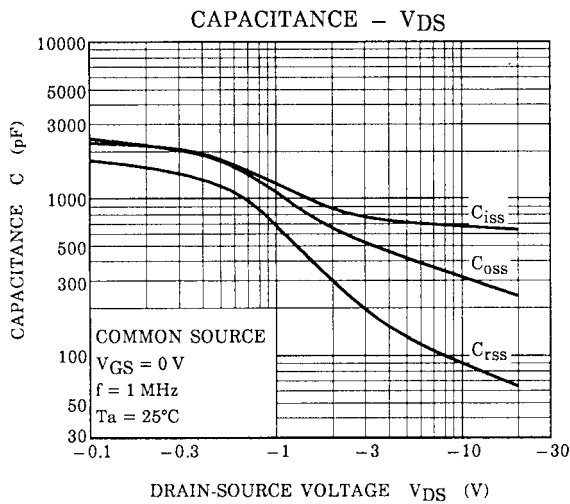
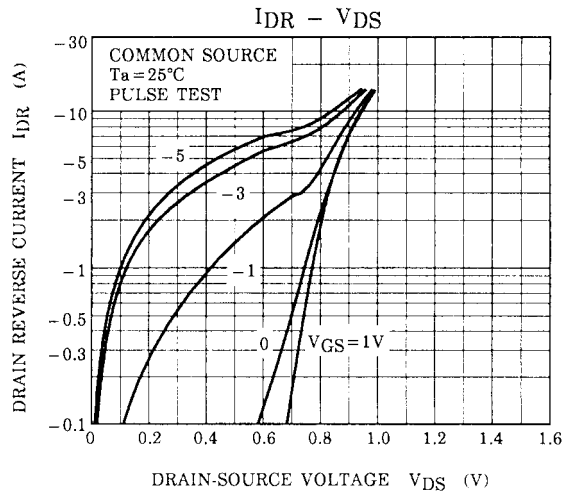
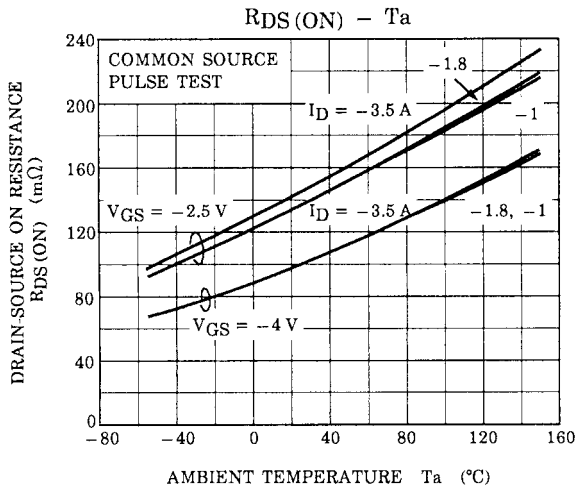
Electrical Characteristics (Ta = 25°C)

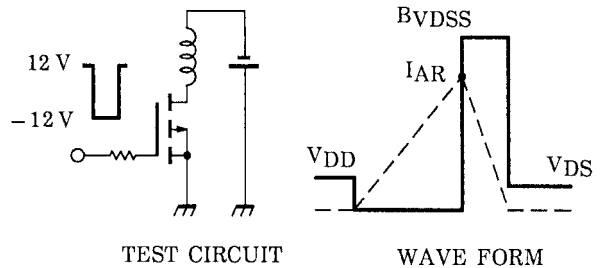
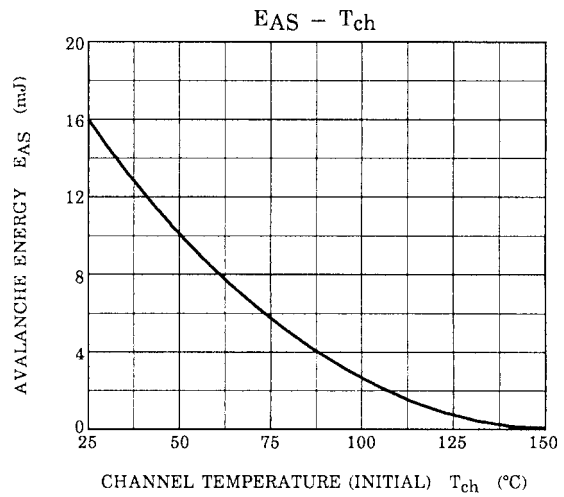
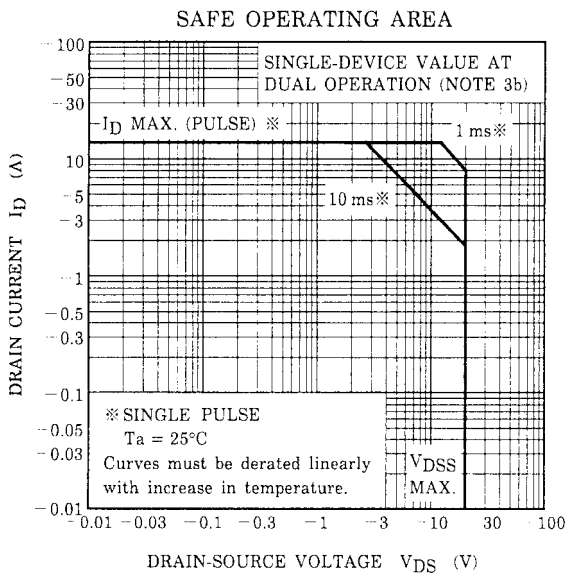
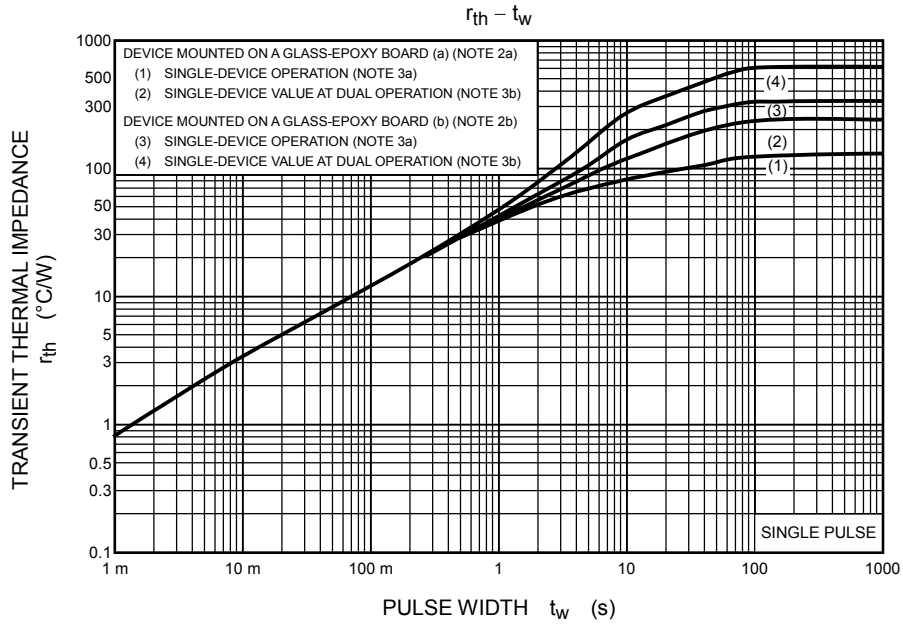
| Characteristics | | Symbol | Test Condition | Min | Typ. | Max | Unit |
|---|---------------|---------------|--|------|------|----------|---------------|
| Gate leakage current | | I_{GSS} | $V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$ | — | — | ± 10 | μA |
| Drain cut-OFF current | | I_{DSS} | $V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$ | — | — | -10 | μA |
| Drain-source breakdown voltage | | $V_{(BR)DSS}$ | $I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$ | -20 | — | — | V |
| Gate threshold voltage | | V_{th} | $V_{DS} = -10 \text{ V}, I_D = -200 \mu\text{A}$ | -0.5 | — | -1.1 | V |
| Drain-source ON resistance | | $R_{DS(ON)}$ | $V_{GS} = -2.5 \text{ V}, I_D = -1.8 \text{ A}$ | — | 135 | 170 | m Ω |
| | | $R_{DS(ON)}$ | $V_{GS} = -4 \text{ V}, I_D = -1.8 \text{ A}$ | — | 100 | 120 | |
| Forward transfer admittance | | $ Y_{fs} $ | $V_{DS} = -10 \text{ V}, I_D = -1.8 \text{ A}$ | 2.5 | 5 | — | S |
| Input capacitance | | C_{iss} | $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | — | 680 | — | pF |
| Reverse transfer capacitance | | C_{rss} | | — | 90 | — | |
| Output capacitance | | C_{oss} | | — | 310 | — | |
| Switching time | Rise time | t_r | <p>$I_D = -1.8 \text{ A}$ $V_{GS} = 0 \text{ V}$ $V_{GS} = -5 \text{ V}$ 4.7Ω $R_L = 5.6 \Omega$ $V_{DD} = -10 \text{ V}$ $Duty \leq 1\%, t_w = 10 \mu\text{s}$</p> | — | 17 | — | ns |
| | Turn-ON time | t_{on} | | — | 24 | — | |
| | Fall time | t_f | | — | 20 | — | |
| | Turn-OFF time | t_{off} | | — | 63 | — | |
| Total gate charge (Gate-source plus gate-drain) | | Q_g | $V_{DD} \approx -16 \text{ V}, V_{GS} = -5 \text{ V}, I_D = -3.5 \text{ A}$ | — | 16 | — | nC |
| Gate-source charge | | Q_{gs} | | — | 10 | — | |
| Gate-drain ("miller") charge | | Q_{gd} | | — | 6 | — | |

Source-Drain Ratings and Characteristics (Ta = 25°C)

| Characteristics | | Symbol | Test Condition | Min | Typ. | Max | Unit |
|-------------------------|----------------|-----------|---|-----|------|-----|------|
| Drain reverse current | Pulse (Note 1) | I_{DRP} | — | — | — | -14 | A |
| Forward voltage (diode) | | V_{DSF} | $I_{DR} = -3.5 \text{ A}, V_{GS} = 0 \text{ V}$ | — | — | 1.2 | V |







$T_{ch} = 25^{\circ}\text{C}$ (Initial)
 Peak $I_{AR} = -3.5\text{ A}$, $R_G = 25\ \Omega$ $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$
 $V_{DD} = -16\text{ V}$, $L = 1.0\text{ mH}$

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